	REVISIONS																									
LTR	DESCRIPTION											DAT	E (Y	R-MO	-DA)	A	PPR	OVEC)							
А	Tec	hnic	ca l	chai	agra iges iges	in	tab	le I		.1c	and	fig	ure	3.					19	988	NOV	30	W	RC.	10	
CUF	CURRENT CAGE CODE 67268																									
REV					Щ			_	ļ					L		_				L	L					
SHEET				_	Ш				_	_	<u></u>		<u> </u>	L		_				L					<u> </u>	
REV				<u> </u>	Щ		<u> </u>	<u> </u>	<u> </u>		_	<u> </u>	<u> </u>	<u>Ļ</u> .	Ь.	_				_						Ш
SHEET		-					<u> </u>	<u> </u>	<u> </u>	ļ	<u> </u>	_		L	1	_						<u> </u>				Щ
REV STAT		⊢	RE'			Α	Α	Α	Α	Α	Α	Α	Α	Α	Α	Α	A	Ą					-		H	Н
PMIC N/A	١		SHE	:E 1		PREI	2 PARE	3 D BY		<u>5</u>	6	7 	8	9	10		12	13						<u></u>		닉
STANDARDIZED MILITARY DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE						CHECKED BY Ray Monnin APPROVED BY DRAWING APPROVAL DATE 12 AUGUST 1987						MICROCIRCUIT, DIGITAL ADVANCED C 1-0F-8 DECODER/DEMULTIPLEXER, MO SILICON. SIZE CAGE CODE A 67268 - 5962-				CMOS ONOL	ітні	\dashv								
DEPARTMENT OF DEFENSE						REV	NOISI	LEV	EL /	١				1	SI	HEE		1	-		F	13				\exists

DESC FORM 193-1 SEP 87

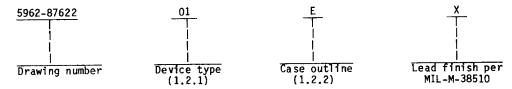
□ U.S. GOVERNMENT PRINTING OFFICE: 1987 — 748-129/60912

5962-E1060

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.



- 1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with $1.\overline{2.1}$ of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".
 - 1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54AC138	1-of-8 decoder/demultiplexer

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
Ē	D-2 (16-lead, .840" x .310" x .200") dual-in-line package
F	F-5 (16-lead, .440" x .285" x .085") flat package C-2 (20-terminal, .358" x .358" x .100") square chip carrier package

1.3 Absolute maximum ratings.

1/ Unless otherwise specified, all voltages are referenced to GND.

Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions in accordance with method 5004 of MIL-STD-883.

STANDARDIZED MILITARY DRAWING	SIZE A			5962-87622	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	•	SHEET 2	

DESC FORM 193A SEP 87

± U. S. GOVERNMENT PRINTING OFFICE: 1988—550-547

1.4 Recommended operating conditions.
Supply voltage (V_{CC}) $3/$ 3.0 V dc to 5.5 V dc Input voltage 0.0 V dc to V_{CC} Output voltage 0.0 V dc to V_{CC} Case operating temperature range (V_{CC}) 55°C to +125°C Input rise or fall times:
VCC = 3.6 V 0 to 116 ns (10-90 percent, 40 ns/V) VCC = 5.5 V 0 to 88 ns (10-90 percent, 20 ns/V)
2. APPLICABLE DOCUMENTS
2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.
SPECIFICATION
MILITARY
MIL-M-38510 - Microcircuits, General Specification for.
STANDARD
MILITARY
MIL-STD-883 - Test Methods and Procedures for Microelectronics.
(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)
2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
3. REQUIREMENTS
3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
3.2 <u>Design, construction</u> , and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
3.2.2 Truth table. The truth table shall be as specified on figure 2.
3.2.3 Logic diagram. The logic diagram shall be as specified on figure 1.
3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
Operation from 2.0 V dc to 3.0 V dc is provided for compatibility with data retention and battery backup systems. Data retention implies no input transitions and no stored data loss with the following conditions: $V_{IH} \geq 70$ percent V_{CC} , $V_{IL} \leq 30$ percent V_{CC} , $V_{OH} \geq 70$ percent V_{CC} at 20 μ A.

STANDARDIZED SIZE A 5962-87622 MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 REVISION LEVEL SHEET 3

DESC FORM 193A SEP 87

Test	 Symbol	Condition	Conditions -55°C <u><</u> T _C <u><</u> +125°C			ts	Unit
		-55°C < T _C <	subgroups	Min	Max		
High-level output voltage	v _{OH}	VIN = VIH or VIL	V _{CC} = 3.0 V	1, 2, 3	2.9	ļ	V
1/		I _{OH} = -50 μA 	V _{CC} = 4.5 V	T 1	4.4		Γ <u> </u>
	 		V _{CC} = 5.5 V		5.4		Г
		VIN = VIH or VIL	V _{CC} = 3.0 V		2.4		,
		V _{IN} = V _{IH} or V _{IL} I _{OH} = -24 mA	V _{CC} = 4.5 V	 	3.7		
		"	V _{CC} = 5.5 V	- 	4.7		
		$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{IOH} = -50 \text{ mA}$	V _{CC} = 5.5 V		3.85		<u>-</u>
Low-level output volta	age V _{OL}	V _{IN} = V _{IH} or V _{IL} I _{OL} = 50 µA	V _{CC} = 3.0 V	1, 2, 3	1	0.1	٧
1/			V _{CC} = 4.5 V		! 	0.1	
	 		V _{CC} = 5.5 V]	0.1	
		VIN = VIH or VIL	V _{CC} = 3.0 V			0.5	
	 	V _{IN} = V _{IH} or V _{IL} I _{OL} = 24 mA	V _{CC} = 4.5 V] 	0.5	
			V _{CC} = 5.5 V] 	0.5	Γ _
		VIN = VIH or VIL	V _{CC} = 5.5 V			1.65	
See footnotes at end	of table.	•					

A

REVISION LEVEL

DESC FORM 193A SEP 87

★ U. S. GOVERNMENT PRINTING OFFICE: 1988—560-547

5962-87622

SHEET

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

Test	Symbol		Condi -55°C <u><</u> T _C	tions	Group A	Lim	Uni	
	 		-55 6 2 16	<u> </u>	subgroups	Min	Max	
High-level input voltag $\frac{2}{}$	le A ^{IH}			$V_{CC} = 3.0 \text{ V}$		2.1	! 	 v
				V _{CC} = 4.5 V	T	3.15		Γ
				V _{CC} = 5.5 V		3.85		Γ
Low-level input voltage $\frac{2}{}$	VIL			V _{CC} = 3.0 V			0.9	i L v
				V _{CC} = 4.5 V			1.35	Г
				V _{CC} = 5.5 V	→ †		1.65	-
Input leakage current	IIL	V _{IN} = 0.	.o v	V _{CC} = 5.5 V	1, 2, 3		-1.0	μА
	IIH	V _{IN} = 5.	.5 V				1.0	•
Quiescent current	Іссн	 V _{IN} = V _C V _{CC} = 5.	C or GND		1, 2, 3		160	μА
	ICCL	 					160	
Input capacitance	CIN	 See 4.3.	1c		4		8.0	рF
Power dissipation 3/ capacitance	CPD	See 4.3.	1c		4		90	pF
unctional tests	 	 Tested a at V _{CC} = 	t V _{CC} = 3.0 5.5 V, see	V and repeated 4.3.1d	7,8			
ropagat <u>io</u> n delay time An to On		 T _C = +25 C _L = 50	pF	V _{CC} = 3.0 V	9 1	1.0	12.5	ns
<u>4</u> /	1	RE = 500 See figur 	Ω	V _{CC} = 4.5 V	† † ! !	1.0	10.0	
	t _{PLH}	Г 		VCC = 3.0 V	† †- ! ! ! !	1.0	13.0	
				V _{CC} = 4.5 V	† †- ! !	1.0	10.0	
e footnotes on next pag	e.							
STANDARDIZ MILITARY DRA			SIZE A		E	962-8762	2	
DEFENSE ELECTRONICS S				REVISION LEV		SHEET		

DESC FORM 193A SEP 87

TABLE I. Electrical performance characteristics - Continued. Test Symbol | Conditions Group A Limits Unit -55°C < T_C < +125°C subgroups Min Max $|T_{C} = -55^{\circ}C, +125^{\circ}C$ Propagation delay time $V_{CC} = 3.0 V$ 10, 11 15.0 tPHL 1.0 ns $|C_L = 50 \text{ pF}$ $|R_L = 500\Omega$ An to On 4/ See figure 3 $V_{CC} = 4.5 \text{ V}$ 11.5 1.0 16.0 tpLH $V_{CC} = 3.0 V$ 1.0 $V_{CC} = 4.5 V$ 12.0 1.0 $T_{C} = +25^{\circ}C$ $C_{L} = 50 \text{ pF}$ $R_{L} = 500\Omega$ $\begin{array}{c} \text{Propagation delay time} \\ \text{E}_1 \text{ to E}_2 \text{ to } \overline{\text{On}} \end{array}$ $V_{CC} = 3.0 \text{ V}$ 9 13.5 tpHL 1.0 ns $V_{CC} = 4.5 \text{ V}$ |See figure 3 4/ 1.0 10.5 15.0 $V_{CC} = 3.0 V$ 1.0 tpLH $V_{C\dot{C}} = 4.5 \text{ V}$ 11.0 1.0 |T_C = -55°C, +125°C |C_L = 50 pF |R_L = 500Ω |See figure 3 10, 11 1.0 15.5 t_{PHL} $V_{CC} = 3.0 \text{ V}$ $V_{CC} = 4.5 \text{ V}$ 12.0 1.0 $V_{CC} = 3.0 V$ 1.0 16.5 tPLH $V_{CC} = 4.5 V$ 13.0 1.0

See footnotes at end of table.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A

5962-87622

REVISION LEVEL
A

6

DESC FORM 193A SEP 87

TABL	E I. <u>E1</u>	ectrical performance	characteristics	- Continued	•		
Test	Symbol		ons	Group A	Lim	Unit	
		-95 C < 1C <	+125 C	subgroups	Min	Max	!
Propagation delay time E3 to On	t _{PHL}	T _C = +25°C C _L = 50 pF	$V_{CC} = 3.0 \text{ V}$	9	1.0	13.0	l Ins I
<u>4</u> /		R _L = 500Ω See figure 3	V _{CC} = 4.5 V	T T	1.0	9.0	[]
	t _{PLH}	T 	V _{CC} = 3.0 V		1.0	15.5	l I
	[] 		V _{CC} = 4.5 V	† †	1.0	11.5	
	t _{PHL}	 T _C = -55°C, +125°C C _L = 50 pF	V _{CC} = 3.0 V	10, 11	1.0	15.0	T
	 	R[= 500Ω See figure 3 	V _{CC} = 4.5 V	T T	1.0	11.0	-
	t _{PLH}	Г 	V _{CC} = 3.0 V	T †	1.0	17.0	-
			V _{CC} = 4.5 V	T Ť	1.0	13.5	-

- $^{1/}$ V_{OH} and V_{OL} tests will be tested at V_{CC} = 4.5 V. All other voltages are guaranteed, if not tested. Limits shown apply to operation at V_{CC} = 5.0 V ±0.5 V. Transmission driving tests are performed at V_{CC} = 5.5 V with a 2 ms duration maximum.
- $\underline{2}/$ V_{IH} and V_{IL} tests are guaranteed by the V_{OH} and V_{OL} tests.
- Power dissipation capacitance (CpD), determines the dynamic power consumption, $P_D = (C_{PD} + C_L) V_{CC} 2 f + I_{CC} V_{CC}$, and the dynamic current consumption (I_S) is, $I_S = (C_{PD} + C_L) V_{CC} f + I_{CC}$.
- AC limits at 5.5 V V_{CC} are equal to limits at 4.5 V V_{CC} and guaranteed by testing at 4.5 V V_{CC}. Minimum ac guaranteed for 5.5 V V_{CC} by guardbanding 4.5 V V_{CC} limits to 1.5 ns (minimum).

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A
5962-87622

REVISION LEVEL
A
7

DESC FORM 193A SEP 87

せ U. S. GOVERNMENT PRINTING OFFICE: 1988--550-647

- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- 3.4 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. OUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening.</u> Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method $\overline{5005}$ of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 4 ($C_{\rm IN}$ and $C_{\rm PD}$ measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance. Test all applicable pins on five devices with zero failures.
 - d. Subgroup 7 and 8 tests shall verify the truth table as specified on figure 2.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE
A

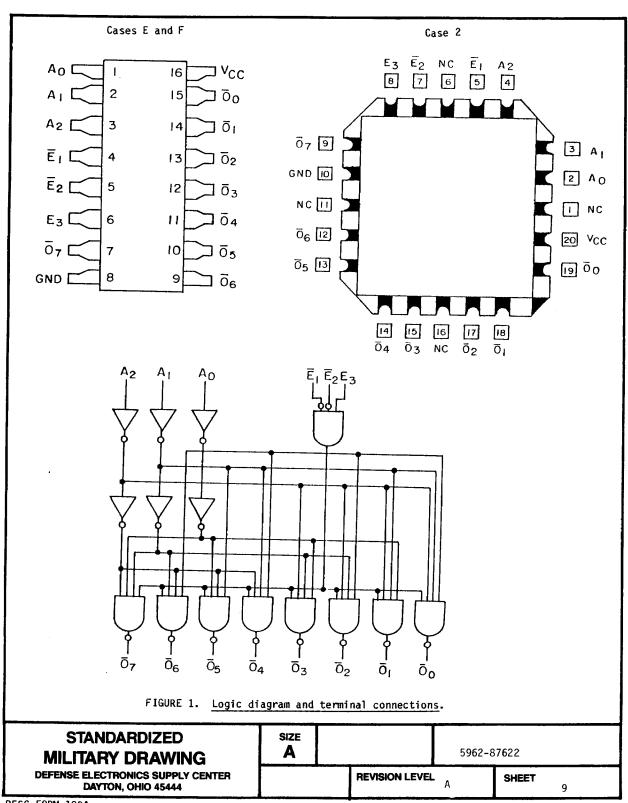
5962-87622

REVISION LEVEL
A

8

DESC FORM 193A SEP 87

U. S. GOVERNMENT PRINTING OFFICE: 1988-550-547



DESC FORM 193A SEP 87

⇒ U. S. GOVERNMENT PRINTING OFFICE: 1988—550-547

	<u> </u>	Inpu	ıts			Outputs								
E ₁	E ₂	E3	A _O	A ₁	A ₂	σ_0	$\overline{\sigma}_1$	₫2	₫3	σ ₄	₀5	Ծ ₆	σ ₇	
Н	Х	X	X	Х	Х	H	Н	н	н	Н	Н	Н	н	
X	Н	X	X	X	X	Н	н	Н	н	Н	Н	Н	н	
X	X	L	x I	X	X	H	Н	Н	Н	Н	н	Н	Н	
L	L	н	L	L	L	L	н	Н	н	н	н	н	н	
L	L	н	Н	L	L	Н	L	Н	Н	Н	н	Н	н	
L	L	н	L	н	L	Н	Н	L	Н	Н	Н	Н	Н	
L	L	н	н	Н	L	н	Н	н	L	Н	Н	н	н	
L	L	н	L	Ł	н	Н	н	н	н	Ł	н	н	Н	
L	Ĺ	н	Н	L	н	Н	Н	Н	Н	Н	L	Н	Н	
L	L	н]	L	Н	н	Н	Н	Н	Н	Н	н	L	н	
L	L	н I I	H	Н	Н I	Н	Н	Н	Н	Н	Н	н	L	

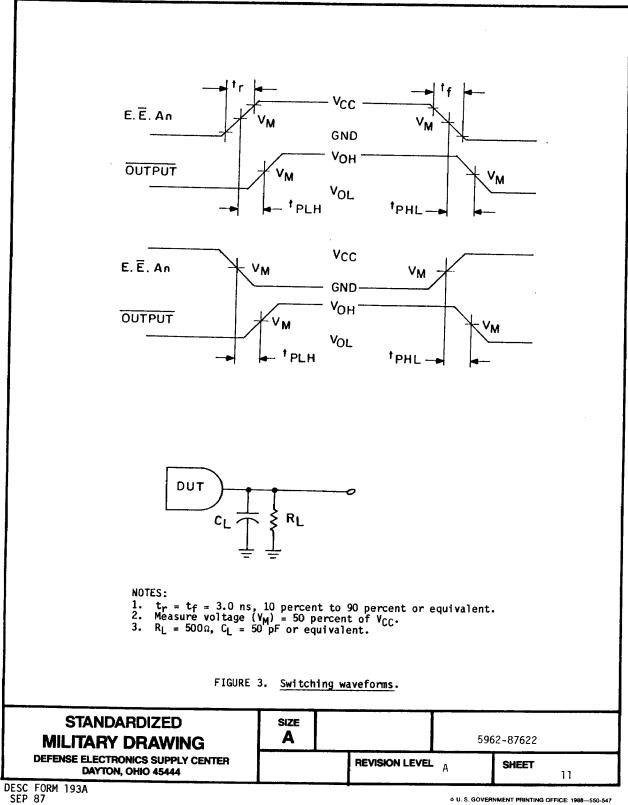
H = HIGH voltage level
L = LOW voltage level
X = Immaterial

FIGURE 2. Truth table

STANDARDIZED MILITARY DRAWING	SIZE A		59	962-87622
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	Α	SHEET 10

DESC FORM 193A SEP 87

☆ U. S. GOVERNMENT PRINTING OFFICE: 1988--550-547



± U. S. GOVERNMENT PRINTING OFFICE: 1988—550-547

TABLE II. Electrical test requirements.

1	MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
1	Interim electrical parameters (method 5004)	
1	Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9
1	Group A test requirements (method 5005)	1, 2, 3, 4, 7, 8, 9, 10, 11
1	Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

 $5.1\,$ Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

STANDARDIZED MILITARY DRAWING	SIZE A			5962-87622	
DEFENSE ELECTRONICS SUPPLY CENTER		REVISION LEV	EL A	SHEET 12	

DESC FORM 193A SEP 87

- 6.2 Replaceability. Replaceability is determined as follows.
 - Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
 - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/75802B--.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.
- 6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /	Replacement military specification part number
5962-8762201EX	07263	54AC138DMQB	M38510/75802BEX
5962-8762201FX	07263	54AC138FMQB	M38510/75802BFX
5962-87622012X	07263	54AC138LMQB	M38510/75802B2X

1/ <u>Caution</u>: Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

07263

Vendor name and address

National Semiconductor 333 Western Avenue South Portland, ME 04106

STANDARDIZED
MILITARY DRAWING

DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444

SIZE A 5962-87622

REVISION LEVEL A SHEET

DESC FORM 193A SEP 87